3.3V CMOS OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS AND 5 VOLT TOLERANT I/O

IDT74LVC573A

FEATURES:

- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015;
 > 200V using machine model (C = 200pF, R = 0)
- 1.27mm pitch SOIC, 0.65mm pitch SSOP, 0.635mm pitch QSOP, 0.65mm pitch TSSOP packages
- Extended commercial range of 40°C to +85°C
- $VCC = 3.3V \pm 0.3V$, Normal Range
- Vcc = 2.3V to 3.6V, Extended Range
- CMOS power levels (0.4µW typ. static)
- Rail-to-Rail output swing for increased noise margin
- All inputs, outputs and I/O are 5 Volt tolerant
- Supports hot insertion

Drive Features for LVC573A:

- High Output Drivers: ±24mA
- Reduced system switching noise

APPLICATIONS:

- 5V and 3.3V mixed voltage systems
- Data communication and telecommunication systems

DESCRIPTION:

The LVC573A octal transparent D-type latch is built using advanced dual metal CMOS technology. The device features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads, and is particularly suitable for implementing buffer registers, input-output (I/O) ports, bidirectional bus drivers, and working registers.

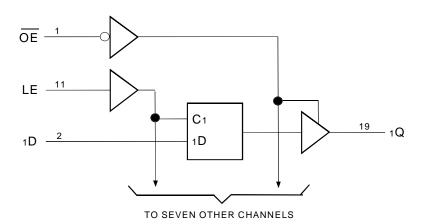
While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels at the D inputs.

A buffered output-enable (OE) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components. OE does not affect the internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The LVC573A has been designed with a ± 24 mA output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

Inputs can be driven from either 3.3V or 5V devices. This feature allows the use of this device as a translator in a mixed 3.3V/5V system environment.

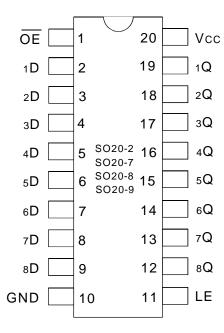
FUNCTIONAL BLOCK DIAGRAM



EXTENDED COMMERCIAL TEMPERATURE RANGE

APRIL 1999

PIN CONFIGURATION



SOIC/ SSOP/ QSOP/ TSSOP TOP VIEW

PIN DESCRIPTION

Pin Names	Description	
Œ	Output-enable Input (Active LOW)	
LE	Latch-enable Input	
хD	Data Inputs	
Qx	3-State Outputs	

ABSOLUTE MAXIMUM RATINGS (1)

		•	
Symbol	Description	Max.	Unit
VTERM(2)	Terminal Voltage with Respect to GND	- 0.5 to +6.5	V
VTERM(3)	Terminal Voltage with Respect to GND	- 0.5 to +6.5	V
Tstg	Storage Temperature	- 65 to +150	°C
Іоит	DC Output Current	- 50 to +50	mA
lıĸ	Continuous Clamp Current,	- 50	mA
Іок	VI < 0 or Vo < 0		
Icc	Continuous Current through	±100	mA
Iss	each Vcc or GND		
			8LVC

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- 2. Vcc terminals.
- 3. All terminals except Vcc.

CAPACITANCE (TA = $+25^{\circ}$ C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Тур.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	4.5	6	pF
Соит	Output Capacitance	Vout = 0V	5.5	8	pF
CI/O	I/O Port Capacitance	VIN = 0V	6.5	8	pF

8LVC Link

NOTE:

1. As applicable to the device type.

FUNCTION TABLE (each latch)⁽¹⁾

	Inputs		Outputs
ŌĒ	LE	хD	Ох
L	Н	Н	Н
L	Н	L	L
L	L	Х	Q_0
Н	Х	Χ	Z

NOTE:

- 1. H = HIGH Voltage Level
 - L = LOW Voltage Level
 - X = Don't Care
 - Z = High-Impedance
 - $\mathbf{Q}_0 = \mathbf{Level}$ of \mathbf{Q} before the indicated steady-state input conditions were established

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition: TA = - 40°C To +85°C

Symbol	Parameter	7	Test Conditions	Min.	Typ. ⁽¹⁾	Max.	Unit
VIH	Input HIGH Voltage Level	Vcc = 2.3V to 2.7V		1.7	_	_	٧
		Vcc = 2.7V to 3.6V		2	_		
VIL	Input LOW Voltage Level	Vcc = 2.3V to 2.7V		_	_	0.7	٧
		Vcc = 2.7V to 3.6V		_	_	0.8	
lih lil	Input Leakage Current	Vcc = 3.6V	VI = 0 to 5.5V	_	_	±5	μA
lozн	High Impedance Output Current	Vcc = 3.6V	Vo = 0 to 5.5V	_	_	±10	μA
lozL	(3-State Output pins)						
loff	Input/Output Power Off Leakage	Vcc = 0V, Vin or Vo	$V_{CC} = 0V$, V_{IN} or $V_{O} \le 5.5V$		_	±50	μA
VIK	Clamp Diode Voltage	Vcc = 2.3V, lin = -1	8mA	_	- 0.7	- 1.2	٧
VH	Input Hysteresis	Vcc = 3.3V		_	100	_	mV
ICCL ICCH	Quiescent Power Supply Current	Vcc = 3.6V	VIN = GND or Vcc	_	_	10	μA
Iccz			$3.6 \le VIN \le 5.5V^{(2)}$	_	_	10	1
Δlcc	Quiescent Power Supply Current Variation	· ·	One input at Vcc - 0.6V, other inputs at Vcc or GND		_	500	µA

NOTES

1. Typical values are at Vcc = 3.3V, +25°C ambient.

2. This applies in the disabled state only.

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Cor	Min.	Max.	Unit	
Vон	Output HIGH Voltage	Vcc = 2.3V to 3.6V	IOH = - 0.1mA	Vcc - 0.2	ı	V
		Vcc = 2.3V	IOH = -6mA	2	_	
		Vcc = 2.3V	IOH = - 12mA	1.7	_	
		Vcc = 2.7V		2.2	_	
		Vcc = 3.0V		2.4	_	
		Vcc = 3.0V	IOH = - 24mA	2.2	_	
Vol	Output LOW Voltage	Vcc = 2.3V to 3.6V	IOL = 0.1mA	_	0.2	V
		Vcc = 2.3V	Iol = 6mA	-	0.4	
			IoL = 12mA	_	0.7	
		Vcc = 2.7V	I _{OL} = 12mA	_	0.4	
		Vcc = 3.0V	IoL = 24mA	_	0.55	8LVC Link

NOTE:

1. VIH and VIL must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate Vcc range. TA = - 40°C to +85°C.

OPERATING CHARACTERISTICS, Vcc = 3.3V \pm 0.3V, T_A = 25°C

Symbol	Parameter	Test Conditions	Typical	Unit
CPD	Power dissipation capacitance per latch outputs enabled	CL = 0pf, f = 10Mhz	37	pF
CPD	Power dissipation capacitance per latch outputs disabled		4	pF

SWITCHING CHARACTERISTICS (1)

		Vcc = 2.	5V±0.2V	Vcc =	= 2.7V	Vcc = 3.	3V±0.3V	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
tplh	Propagation Delay	_	_	_	7.7	1.5	6.9	ns
tphl	xD to xQ							
tPLH	Propagation Delay	_	_	_	8.4	2	7.7	ns
tphl	LE to xQ							
tpzh	Output Enable Time	_	_	_	8.5	1.5	7.5	ns
tpzl	Œ to xQ							
tphz	Output Disable Time	_	_	_	7	1.6	6.5	ns
tPLZ	Œ to xQ							
tw	Pulse Duration, LE HIGH	_	_	3.3	_	3.3	_	ns
tsu	Setup Time, data before LE↓	_		2	_	2	_	ns
tH	Hold Time, data after LE↓	_	_	1.5	_	1.5	_	ns
tsk(0)	Output Skew ⁽²⁾	_	-	-	_	-	1	ns

NOTES:

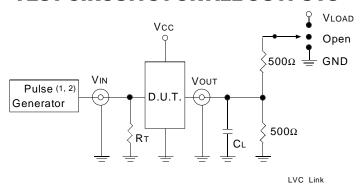
- 1. See test circuits and waveforms. TA = -40°C to + 85°C.
- 2. Skew between any two outputs of the same package and switching in the same direction.

TEST CIRCUITS AND WAVEFORMS

TEST CONDITIONS

Symbol	$V_{CC}^{(1)} = 3.3V \pm 0.3V$	$V_{CC}^{(1)} = 2.7V$	$V_{CC}^{(2)} = 2.5V \pm 0.2V$	Unit
VLOAD	6	6	2 x Vcc	٧
VIH	2.7	2.7	Vcc	٧
VT	1.5	1.5	Vcc/2	٧
VLZ	300	300	150	mV
VHZ	300	300	150	mV
CL	50	50	30	pF VC Link

TEST CIRCUITS FOR ALL OUTPUTS



DEFINITIONS:

CL= Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to ZouT of the Pulse Generator.

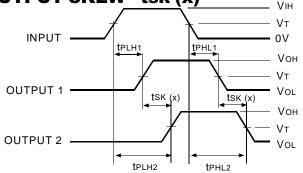
NOTES:

- 1. Pulse Generator for All Pulses: Rate ≤ 10MHz: tF ≤ 2.5ns: tR ≤ 2.5ns.
- 2. Pulse Generator for All Pulses: Rate \leq 10MHz; tF \leq 2ns; tR \leq 2ns.

SWITCH POSITION

Test	Switch
Open Drain	Vload
Disable Low	
Enable Low	
Disable High	GND
Enable High	
All Other tests	Open

OUTPUT SKEW - tsk (x)

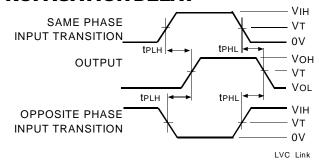


tsk(x) = |tPLH2 - tPLH1| or |tPHL2 - tPHL1|

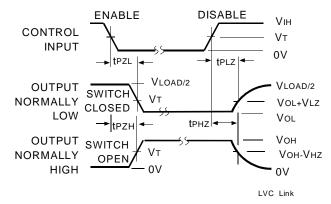
NOTES: 1. For tsk(o) OUTPUT1 and OUTPUT2 are any two outputs.

2. For tsk(b) OUTPUT1 and OUTPUT2 are in the same bank.

PROPAGATION DELAY



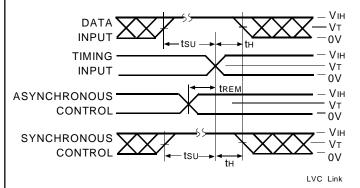
ENABLE AND DISABLE TIMES



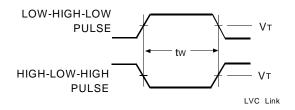
NOTE:

 Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

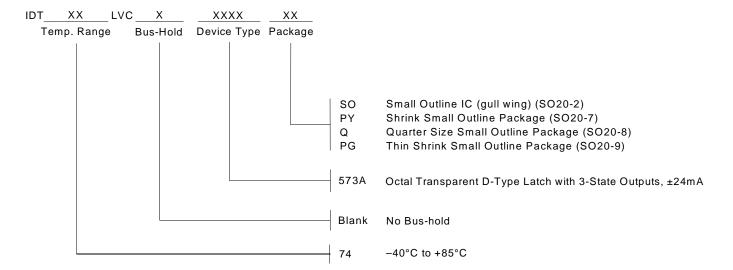
SET-UP, HOLD, AND RELEASE TIMES



PULSE WIDTH



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